



国际口腔医学杂志 » 2010, Vol. 37 » Issue (3) :355-355~358 DOI: 10.3969/j.issn.1673-5749.2010.

综述

[最新目录](#) | [下期目录](#) | [过刊浏览](#) | [高级检索](#)

<< 前一篇 | 后一篇 >>

半导体激光在下颌第三磨牙拔除术后并发症预防的应用进展

钟时春综述 张志光审校

中山大学光华口腔医学院·附属口腔医院·口腔医学研究所 广东 广州 510055

Effectiveness of semiconductor laser irradiation in the prevention of postoperative complications after extraction of mandibular third molar

ZHONG Shi-chun, ZHANG Zhi -guang.

Research Institute of Stomatology, Hospital of Stomatology, Guanghua School of St

摘要

参考文献

相关文章

Download: [PDF \(121KB\)](#) [HTML \(OKB\)](#) Export: BibTeX or EndNote (RIS) [Supporting Info](#)

摘要 下颌阻生第三磨牙拔除术是牙槽外科一项较为复杂的手术。其术后的主要并发症为拔牙后疼痛、面部肿胀反应、感染、干槽症、拔牙术后出血、颞下颌关节紊乱综合征和开口受限等。半导体激光器发展至今，在诸多领域中都得到了广泛应用。本文通过对激光生物学效应的探讨，对半导体激光在下颌第三磨牙拔除术后并发症预防方面的作用作一综述。

关键词： 半导体激光 下颌第三磨牙 并发症

Abstract: The extraction of mandibular third tooth is a complicated operation in alveolar surgery. The main complications are pain, swelling, infection, dry socket, bleeding, temporomandibular joint disorders and restrict opening. Semiconductor laser is widely used in a good many fields. The review discusses the mechanism of semiconductor laser and summarizes effectiveness in the prevention of postoperative complication after mandibular third tooth extraction.

Keywords:

Received 2009-09-06;

Corresponding Authors: 张志光

引用本文:

钟时春综述 张志光审校.半导体激光在下颌第三磨牙拔除术后并发症预防的应用进展[J] 国际口腔医学杂志, 2010,V37(3): 355-355~358

ZHONG Shi-chun, ZHANG Zhi -guang..Effectiveness of semiconductor laser irradiation in the prevention of postoperative complications after extraction of mandibular third molar[J] , 2010,V37(3): 355-355~358

Service

- ▶ 把本文推荐给朋友
- ▶ 加入我的书架
- ▶ 加入引用管理器
- ▶ Email Alert
- ▶ RSS

作者相关文章

- ▶ 钟时春综述 张志光审校